Issue Classification

Application/Control No.	Applicant(s)/Patent Under Reexamination
10550619	TANAKA ET AL.
Examiner	**Art Unit**
Heyman, John	2871

ORIGINAL

CLASS	SUBCLASS
349	15

CROSS REFERENCE(S)

CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
349	58	161			

INTERNATIONAL CLASSIFICATION

CLAIMED	NON-CLAIMED
G 02F 1 / 1335 (2006.01.01)	

Heyman, John	12/04/2007	ANDREW SCHECHTER PRIMARY EXAMINER 12/10/07	Total Claims Allowed: 5	
(Assistant Examiner)	(Date)			
(Legal Instruments Examiner)	12/18/07 (Date)	Andrew Schechter (Primary Examiner)	12/04/2007 (Date)	O.G. Print Claim(s) 1	O.G. Print Figure 1